Notice of References Cited Application/Control No. 10/076,174 Examiner Michelle Estrada Applicant(s)/Patent Under Reexamination BAUDE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------|----------------|
| * | Α | US-5,534,969 | 07-1996 | Miyake, Eiichi | 355/53 |
| ¥ | В | US-6,259,408 | 07-2001 | Brady et al. | 343/700MS |
| × | С | US-6,589,382 | 07-2003 | Clark et al. | 156/304.3 |
| * | D | US-2003/0160325 | 08-2003 | Yoneda et al. | 257/758 |
| * | Е | US-5,682,228 | 10-1997 | Miyake, Eiichi | 355/75 |
| * | F | US-2001/0026975 | 10-2001 | Ando, Masateru | 438/253 |
| * | G | US-2002/0102811 | 08-2002 | Farrow et al. | 438/401 |
| | Н | US- | | | |
| | ı | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | Ν | | | | | |
| | 0 | | | | | |
| | P | | | | | |
| | α | | | | | |
| | R | | | | | |
| | S | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | w | |
| | х | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.